



*Supplement of*

## **Simulating secondary organic aerosol in a regional air quality model using the statistical oxidation model – Part 2: Assessing the influence of vapor wall losses**

**Christopher D. Cappa et al.**

*Correspondence to:* Christopher D. Cappa (cdcappa@ucdavis.edu)

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The Supplemental Material consists of six figures and two tables.

**Influence of NO<sub>x</sub> Parameterization:** In the manuscript the influence of vapor wall losses was calculated for the low vapor wall loss (VWL) and high VWL cases as:

$$R_{wall}(lowVWL) = \frac{[SOA]_{lowVWL,lowNO_x} + [SOA]_{lowVWL,highNO_x}}{[SOA]_{noVWL,lowNO_x} + [SOA]_{noVWL,highNO_x}} \quad (S1)$$

or

$$R_{wall}(highVWL) = \frac{[SOA]_{highVWL,lowNO_x} + [SOA]_{highVWL,highNO_x}}{[SOA]_{noVWL,lowNO_x} + [SOA]_{noVWL,highNO_x}} \quad (S2)$$

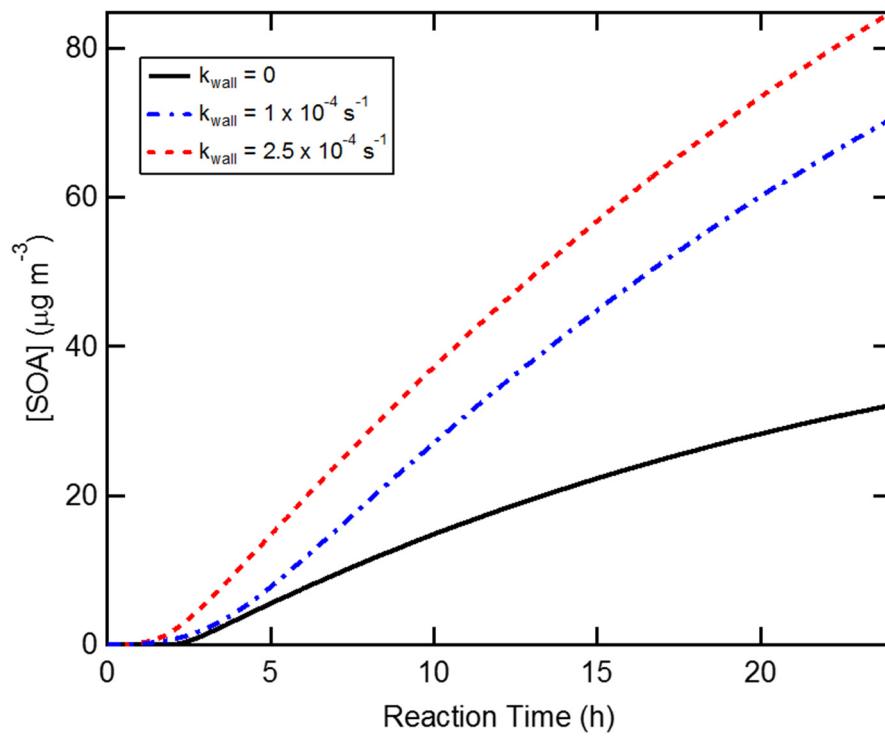
and where “low NO<sub>x</sub>” and “high NO<sub>x</sub>” refer to the experimental conditions under which the experiments were performed to which the SOM was fit (see Table S1). The influence of the NO<sub>x</sub> parameterization for a given VWL case can also be assessed by comparing  $R_{wall}$  values calculated individually for each NO<sub>x</sub> condition:

$$R_{wall}(low\ NO_x) = \frac{[SOA]_{lowVWL,lowNO_x}}{[SOA]_{noVWL,lowNO_x}} \ or = \frac{[SOA]_{highVWL,lowNO_x}}{[SOA]_{noVWL,lowNO_x}} \quad (S3)$$

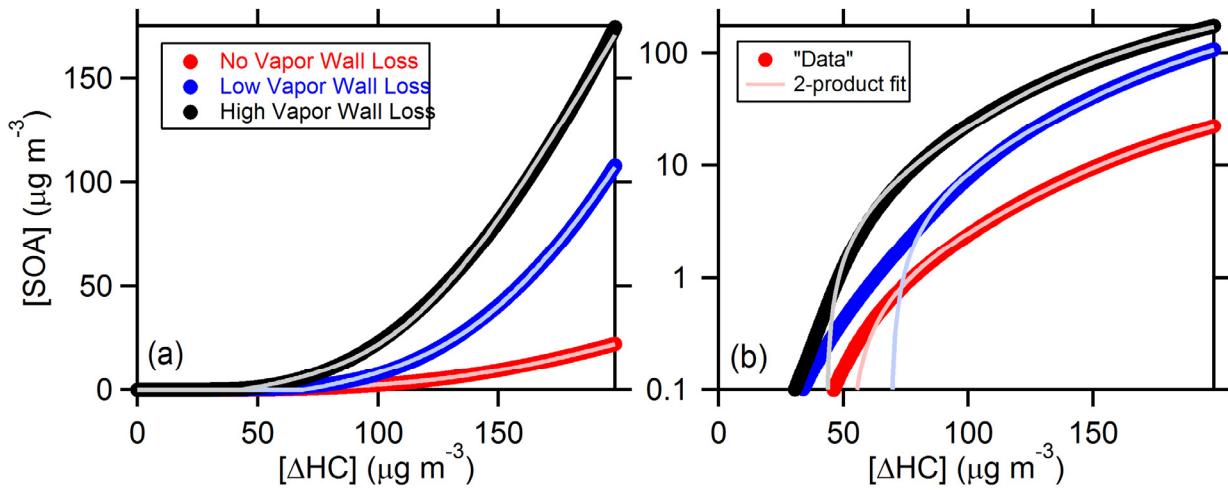
and

$$R_{wall}(high\ NO_x) = \frac{[SOA]_{lowVWL,highNO_x}}{[SOA]_{noVWL,highNO_x}} \ or = \frac{[SOA]_{highVWL,highNO_x}}{[SOA]_{noVWL,highNO_x}} \quad (S4)$$

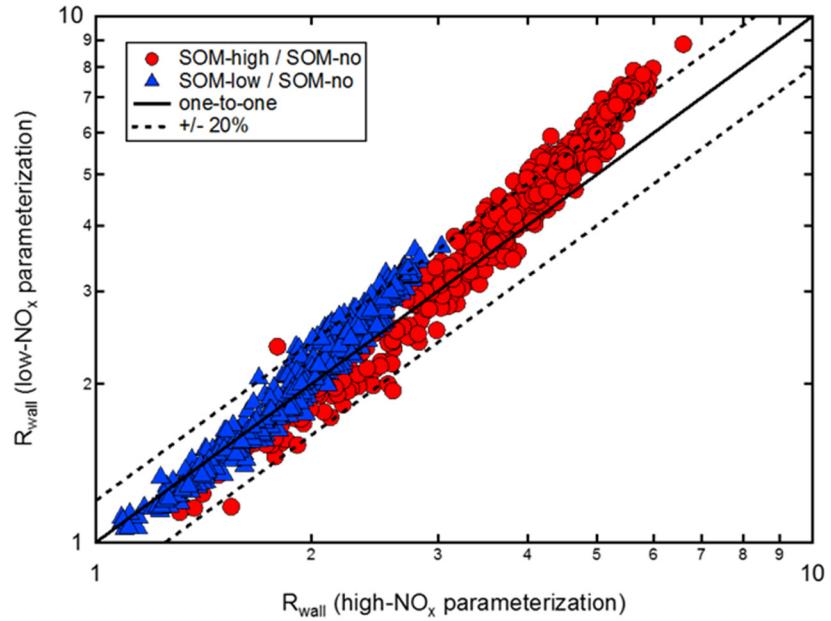
The  $R_{wall}$  values from Eqns. S3 and S4 are compared in Figure S3. It is clear that there is some difference between the simulated  $R_{wall}$  values between the low-NO<sub>x</sub> and high-NO<sub>x</sub> parameterizations, although most points fall close to the one-to-one line. At very low  $R_{wall}$  values, the high-NO<sub>x</sub> parameterization gives slightly lower  $R_{wall}$  than does the low-NO<sub>x</sub> parameterization for both the SOM-lowVWL and SOM-highVWL cases. But as the absolute  $R_{wall}$  values increase the opposite is true. Regardless, the differences between the NO<sub>x</sub>-parameterizations are much smaller than the absolute values of the simulated  $R_{wall}$  values.



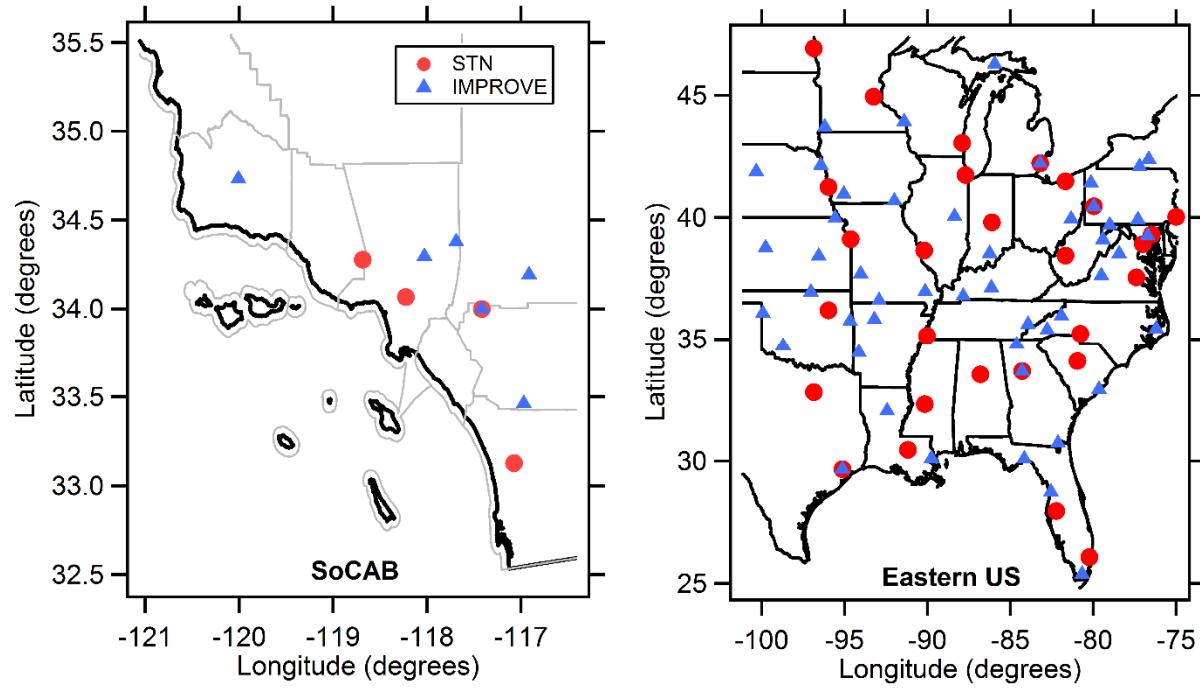
**Figure S1.** Box model simulations of SOA formation using SOM parameters determined from fitting low-NO<sub>x</sub> toluene + OH SOA data assuming  $k_{\text{wall}} = 0, 1 \times 10^{-4}$  and  $2.5 \times 10^{-4} \text{ s}^{-1}$ , but where the simulations are run with  $k_{\text{wall}} = 0 \text{ s}^{-1}$ . Reaction conditions here are  $[\text{toluene}]_{t=0} = 100 \mu\text{g m}^{-3}$  and  $[\text{OH}] = 2 \times 10^6 \text{ molecules cm}^{-3}$ .



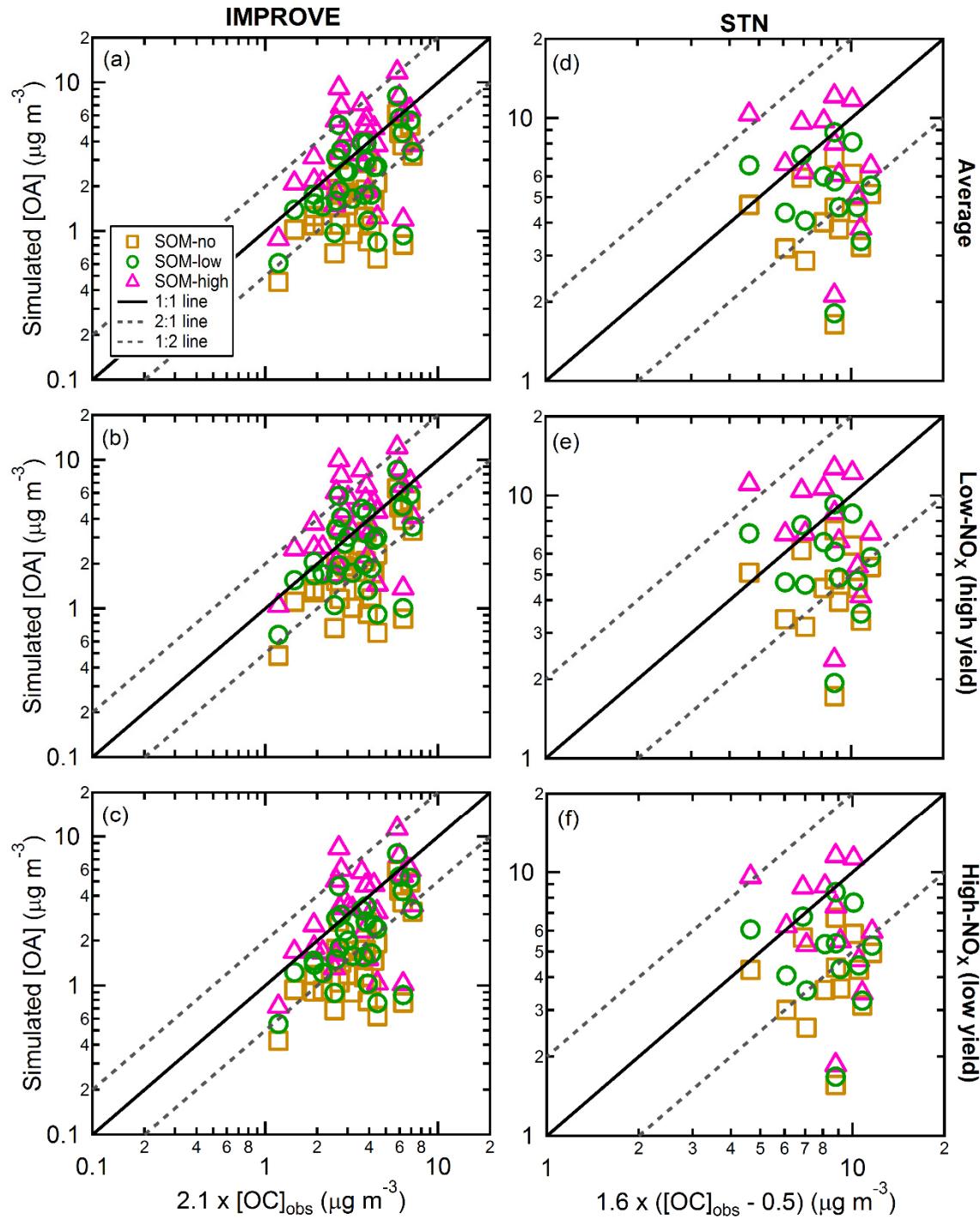
**Figure S2.** Example of 2-product fitting to SOA yield curves for dodecane + OH SOA formed under low- $\text{NO}_x$  conditions. The 2-product model was fit to simulated vapor wall-loss-corrected yield curves (circles) that were generated using the SOM model. The original SOM fits were performed using variable  $k_{\text{wall}}$  values to account for vapor wall losses, but the subsequent simulated yield curves were generated with  $k_{\text{wall}} = 0$ . The lines are colored according to the wall-loss condition used when SOM was fit to the chamber observations, no wall loss (red), low wall loss (blue) and high wall loss (black). The best 2-product fits are shown as solid lines. Panel (a) shows the curves and fits on a linear scale and panel (b) shows the same on a log scale. Note that on a linear scale the deviations between the fit curves and the “data” at low [SOA] is not visibly evident.



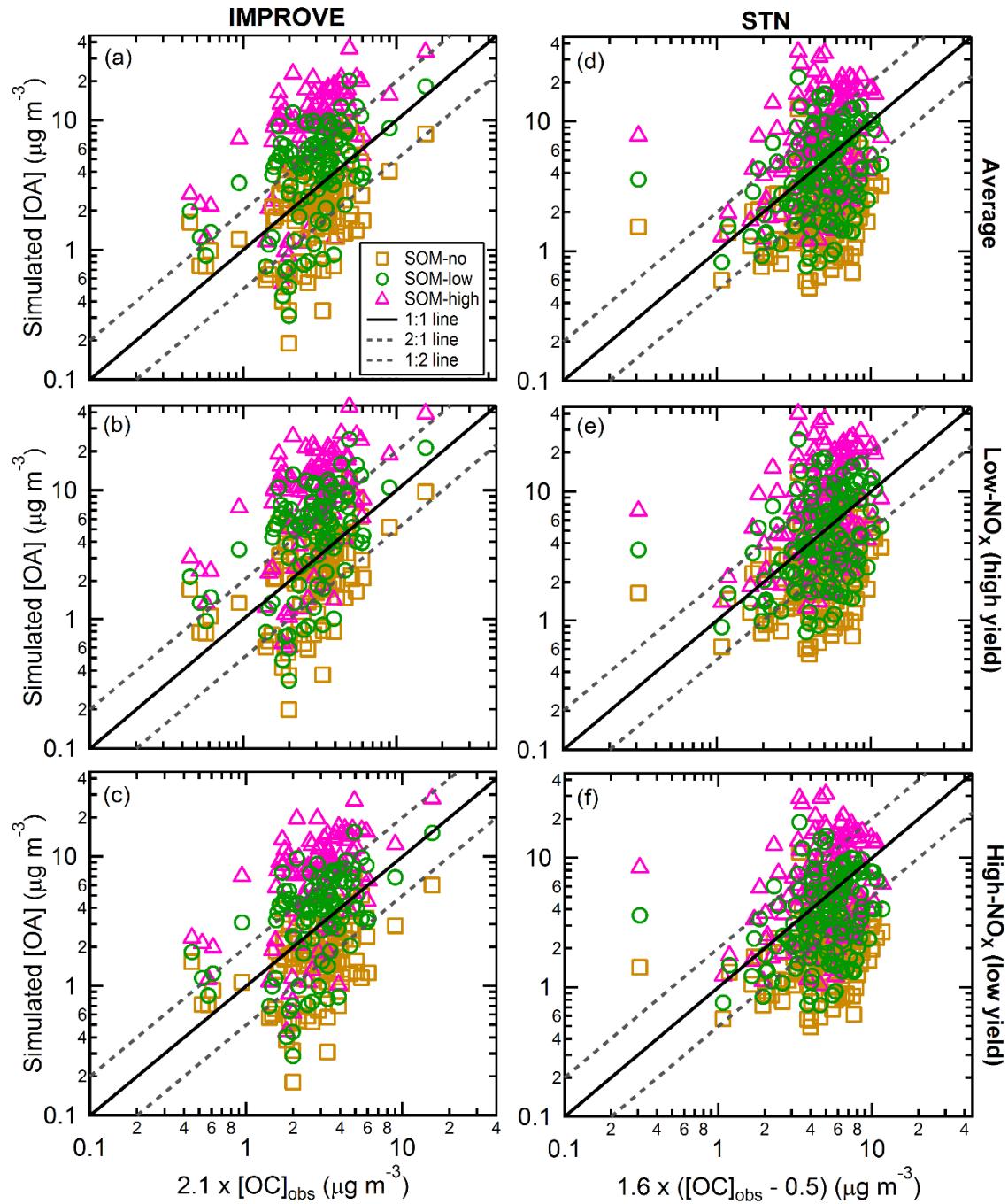
**Figure S3.** Comparison of  $R_{\text{wall}}$  values calculated for the low- $\text{NO}_x$  parameterization (y-axis) or high- $\text{NO}_x$  parameterization (x-axis) for the low vapor wall loss case (blue triangles) and high vapor wall loss case (red circles). The solid black line shows the 1-to-1 relationship and the dashed black lines the +/- 20% deviation from the 1-to-1 line.



**Figure S4.** Map of STN and IMPROVE sites in the (left) SoCAB and (right) eastern US. STN sites are shown as red circles and IMPROVE sites as blue triangles.



**Figure S5.** Scatter plots of simulated versus observed total OA (SOA + POA) concentrations for SoCAB for (left panels) IMPROVE and (right panels) STN sites. Simulation results are shown for SOM-no (orange), SOM-low (green) and SOM-high (pink). Results are reported from simulations run using the (top) average, (middle) low-NO<sub>x</sub> / high-yield, and (bottom) high-NO<sub>x</sub> / low-yield parameterizations.



**Figure S6.** Scatter plots of simulated versus observed total OA (SOA + POA) concentrations for SoCAB for (left panels) IMPROVE and (right panels) STN sites. Simulation results are shown for SOM-no (orange), SOM-low (green) and SOM-high (pink). Results are reported from simulations run using the (top) average, (middle) low- $\text{NO}_x$  / high-yield, and (bottom) high- $\text{NO}_x$  / low-yield parameterizations. Only every other data point (one-in-two) is shown for visual clarity.

**Table S1.** List of best-fit SOM parameters determined by fitting SOM to experimental observations of SOA formation in the Caltech environmental chamber assuming that  $k_{\text{wall}} = 1 \times 10^{-4} \text{ s}^{-1}$  or  $2.5 \times 10^{-4} \text{ s}^{-1}$ .

VOC Precursor Class	SAPRC-11 Species Name	VOC Surrogate	NO <sub>x</sub>	$m_{\text{frag}}$	$\Delta \text{LVP}$	$p_{10}$	$p_{20}$	$p_{30}$	$p_{40}$	Ref. <sup>^</sup>
$k_{\text{wall}} = 1 \times 10^{-4} \text{ s}^{-1}$										
Long Alkanes	ALK5*	dodecane	low	0.677	1.57	0.97	0.023	0.003	0.004	(Cappa et al., 2013; Loza et al., 2014)
			high	0.186	1.45	0.961	0.001	0.002	0.036	
Benzene	Benzene	benzene	low	0.01	2.31	0.324	0.001	0.607	0.068	(Ng et al., 2007)
			high	0.73	1.47	0.018	0.001	0.981	0.001	
Toluene	ARO1	toluene	low	0.843	1.70	0.066	0.001	0.106	0.827	(Zhang et al., 2014)
			high	5	1.37	0.865	0.001	0.065	0.069	
m-xylene	ARO2	m-xylene	low	0.236	1.97	0.001	0.123	0.8	0.075	(Ng et al., 2007)
			high	0.0389	1.46	0.001	0.001	0.905	0.093	
Isoprene	Isoprene	isoprene	low	0.01	2.20	0.097	0.13	0.748	0.025	(Chhabra et al., 2011)
			high	0.745	2.15	0.808	0.189	0.002	0.001	
Terpenes	TRP1/ SESQ <sup>+</sup>	$\alpha$ -pinene	low	0.156	1.89	0.316	0.554	0.087	0.043	(Chhabra et al., 2011)
			high	0.0588	1.92	0.064	0.865	0.063	0.008	
$k_{\text{wall}} = 2.5 \times 10^{-4} \text{ s}^{-1}$										
Long Alkanes	ALK5*	dodecane	low	2	1.83	0.999	0.001	0.001	0.001	(Cappa et al., 2013; Loza et al., 2014)
			high	0.266	1.47	0.965	0.001	0.002	0.032	
Benzene	Benzene	benzene	low	0.0807	1.97	0.637	0.001	0.002	0.360	(Ng et al., 2007)
			high	0.824	1.53	0.008	0.001	0.991	0.001	
Toluene	ARO1	toluene	low	1.31	1.77	0.185	0.001	0.002	0.812	(Zhang et al., 2014)
			high	4.61	1.42	0.856	0.001	0.002	0.141	
m-xylene	ARO2	m-xylene	low	1.08	2.05	0.102	0.001	0.878	0.019	(Ng et al., 2007)
			high	0.0671	1.46	0.001	0.001	0.942	0.056	
Isoprene	Isoprene	isoprene	low	0.0839	2.44	0.096	0.379	0.518	0.007	(Chhabra et al., 2011)
			high	5	1.78	0.874	0.039	0.085	0.001	
Terpenes	TRP1/ SESQ <sup>+</sup>	$\alpha$ -pinene	low	0.305	1.97	0.419	0.426	0.140	0.014	(Chhabra et al., 2011)
			high	0.16	1.91	0.500	0.422	0.070	0.008	

<sup>^</sup>These are the primary references for the experimental data. The data for the specific experiments used are presented in the supplemental material of (Zhang et al., 2014)

\*For SOM, the ALK5 class is separated into long alkane species grouped according to carbon number. See (Jathar et al., 2015) for details.

<sup>+Although the same set of parameters are used to describe the formation of oxidation products and SOA from monoterpenes and sesquiterpenes, the SOA yield from sesquiterpenes is larger than for monoterpenes due to the larger number of carbon atoms comprising sesquiterpenes.</sup>

**Table S2.** Comparison between calculated non-fossil fractions of secondary organic aerosol (SOA) and secondary organic carbon (SOC).

Vapor Wall Loss Case	NO <sub>x</sub> condition	Central LA		Riverside	
		SOA	SOC	SOA	SOC
SOM-no	high-NO <sub>x</sub>	0.27	0.24	0.28	0.25
	low-NO <sub>x</sub>	0.44	0.41	0.40	0.37
SOM-low	high-NO <sub>x</sub>	0.22	0.23	0.27	0.28
	low-NO <sub>x</sub>	0.32	0.30	0.35	0.33
SOM-high	high-NO <sub>x</sub>	0.22	0.25	0.28	0.31
	low-NO <sub>x</sub>	0.33	0.32	0.37	0.36
<hr/>					
Smokey Mountains					
		Atlanta		Smokey Mountains	
		SOA	SOC	SOA	SOC
SOM-no	high-NO <sub>x</sub>	0.10	0.08	0.14	0.12
	low-NO <sub>x</sub>	0.17	0.15	0.15	0.13
SOM-low	high-NO <sub>x</sub>	0.19	0.18	0.27	0.27
	low-NO <sub>x</sub>	0.18	0.17	0.22	0.20
SOM-high	high-NO <sub>x</sub>	0.25	0.27	0.32	0.35
	low-NO <sub>x</sub>	0.20	0.19	0.24	0.23

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